

IN THE
UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s): Karl Joseph Bois et al.

Confirmation No.:

Application No.:

Examiner:

Filing Date: 11/05/03

Group Art Unit:

Title: System and Method for Determining a Dielectric Property Associated with a Substrate

Commissioner for Patents
PO Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

This Information Disclosure Statement is submitted:

(X) under 37 CFR 1.97(b), or
(Within three months of filing national application; or date of entry of national application; or before mailing date of first office action on the merits; whichever occurs last)

() under 37 CFR 1.97(c) together with either a:
() Statement under 37 CFR 1.97(e), or
() a \$180.00 fee under 37 CFR 1.17(p), or
(After the CFR 1.97 (b) time period, but before final action or notice of allowance, whichever occurs first)

() under 37 CFR 1.97 (d) together with a:
() Statement under 37 CFR 1.97(e)(1) or (2), and
() a \$180.00 fee set forth in 37 CFR 1.17(p).
(Filed after final action, a notice of allowance, on or before payment of the issue fee)

Please charge to Deposit Account 08-2025 the sum of \$0.00. At any time during the pendency of this application, please charge any fees required or credit any overpayment to Deposit Account 08-2025 pursuant to 37 CFR 1.25.

(X) Applicant(s) submit herewith Form PTO 1449 - Information Disclosure Statement together with any required copies of patents, publications or other information of which applicant(s) are aware, which applicant(s) believe(s) may be material to the examination of this application and for which there may be a duty to disclose in accordance with 37 CFR 1.56.

() A concise explanation of the relevance of foreign language patents, foreign language publications and other foreign language information listed on PTO Form 1449, as presently understood by the individual(s) designated in 37 CFR 1.56 (c) most knowledgeable about the content is given on the attached sheet, or where a foreign language patent is cited in a search report or other action by a foreign patent office in a counterpart foreign application, an English language version of the search report or action which indicates the degree of relevance found by the foreign office is listed on form PTO 1449 and is enclosed herewith.

It is requested that the information disclosed herein be made of record in this application.

"Express Mail" label no. EV331251483US

Respectfully submitted,

Date of Deposit 11/05/03

Karl Joseph Bois et al.

I hereby certify that this is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service under 37 CFR 1.10 on the date indicated above and is addressed to: Commissioner for Patents, Alexandria, VA 22313-1450.

By Shreen K. Danamraj

By Shreen K. Danamraj

Shreen K. Danamraj

Attorney/Agent for Applicant(s)
Reg. No. 41,696

Typed Name: Shreen K. Danamraj

Date: 11/05/03

PATENT APPLICATION

Sheet 1 of 2

FORM PTO-1449 LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)	ATTY. DOCKET NO.	APPLICATION NO.	CONFIRMATION NO.
	200312072-1		
	APPLICANT Karl Joseph Bois et al.		
	FILING DATE	GROUP	
11/05/03			

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	PUBLICATION DATE	NAME	Pages, Columns, Lines Where Relevant Passages or Figures Appear
1A	6,106,567	08/22/00	Grobman et al.	
1B	2002/0180004	12/05/02	Oggioni et al.	
1C				
1D				
1E				
1F				
1G				
1H				
1I				
1J				
1K				

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	Pages/Columns/Lines Where Relevant Passages/Figures Appear	Check if Translation attached
	1L					
	1M					
	1N					
	1O					
	1P					

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

1Q	<p>Karl J. Bois, Brian Kirk, Michael Tsuk and David Quint; "Simple and Accurate Determination of Complex Permittivity and Skin Effect of FR4 Material in Gigahertz Regime"; Proceedings of the 53rd Electronic Components and Technology Conference; pp. 1277-1282; New Orleans, LA; May 27-30, 2003.</p>
1R	<p>Ari H. Sihvola and Jin Au Kong; "Effective Permittivity of Dielectric Mixtures"; IEEE Transactions of Geoscience and Remote Sensing, Vol. 26, No. 4, July 1988; pp. 420-429.</p>
1S	<p>Michael D. Janezic and Jeffrey A. Jargon; "Complex Permittivity Determination from Propagation Constant Measurements"; IEEE Microwave and Guided Wave Letters, Vol. 9, No. 2, February 1999; pp. 76-78.</p>

EXAMINER

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PATENT APPLICATION

Sheet2 of 2

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	1L					
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	1N					
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	1P					

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

	1Q	Mike Grabois; "Understanding losses is key to state-of-the-art interfacing"; EETimes; February 19, 2003; http://www.eetimes.com/printableArticle?doc_id=OEG20030219S0044 ; 9 pages.
	1R	
	1S	

EXAMINER

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